



Contribution ID: 8

Type: **not specified**

HL-LHC IT String individual system & short circuit tests (WP16/TE-MPE)

The Individual System Tests (IST) and the Short Circuit Tests (SCT) are important intermediary steps in the Hardware Commissioning (HWC) of the HL-LHC IT String. This talk gives an overview of the different IST and SCT planned for the warm powering system, the cryogenic system, the quench detection, and protection systems and the associated procedures. Moreover, the quality control steps and quality assurance of HL-LHC IT String systems will be shown in the presentation. These steps and procedures will also be a cornerstone to prepare the work for the HL-LHC.

Presenter: YAMMINE, Samer (CERN)

Session Classification: Upcoming main activities